

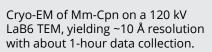
DE-DirectView Camera

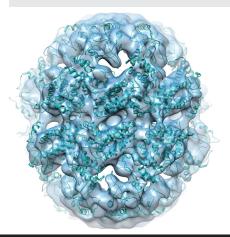
versatile & economical direct detection

delivering | bigger | better | faster | cameras for electron microscopy

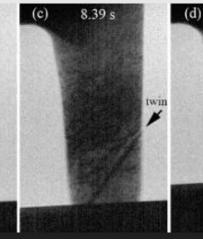
Direct Detection for Transmission Electron Microscopy

- Direct detection device (DDD®) delivers ultra-high speed, extraordinary resolution, and ultra-low noise.
- $4k \times 3k$ (12.6 million) pixels.
- Ideal for a broad range of applications for both materials science (including in situ TEM, 4D-STEM, low-dose, etc.) and biological cryo-EM.
- Reach sub-nanometer resolution with cryo-EM on 120 kV LaB6 TEMs.
- High-speed continuous streaming for in situ TEM movies and motion-corrected imaging.
- Integrated Faraday plate.
- Based on our DE-12 which has a long track record of proven performance.
- Low total cost-of-ownership and exceptional support.
- The most impactful and cost-effective upgrade to a TEM's capabilities.





Frame from an in situ TEM movie at 57 fps. Courtesy of Zhiwei Shan (Xi'an Jiaotong University, China).



Applications



Microscopy





DE-DirectView Camera

email | info@directelectron.com | web | www.directelectron.com | phone | +1 858-384-0291

TEM electron energy pixel array specification single electron SNR sensor design

sensitive to 80 keV – 1.25 MeV $\,|\,$ optimized for 120 - 300 keV 4096 \times 3072 (12.6 million pixels) $\,|\,$ 6.0 μ m pixel pitch

~20:1 (300 kV)

>3T pixel design with on-chip correlated double sampling (CDS)

backthinned | radiation hardened

acquisition frame rate

40 fps max, unbinned full-frame \mid 75 fps max, binned-2× full-frame subarray readout up to 960 fps (4096 × 128) \mid user-selectable hardware frame rate integrating mode

acquisition modes
exposure rate
mounting position
exposure measuremen
sensor protection
computer system
image format

acquisition software

automation

large dynamic range with consistent performance (e.g., >500 e⁻/pixel/s)

fully retractable | mounted on-axis TEM bottom port or in JEOL film drawer

exposure measurement integrated Faraday plate for exposure measurement with each acquisition

integrated sensor protection shutter | TEM blanking/shuttering | failsafe software high-performance computer | Windows 10 | NVidia GPU(s) | up to 48 TB storage

non-proprietary to ensure broad compatibility | TIFF, MRC, AVI, MP4, etc.

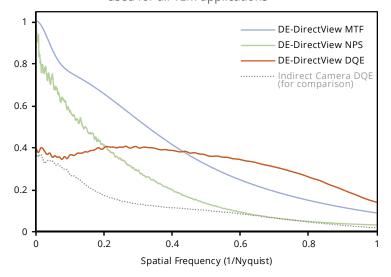
image acquisition: DE-IM (full-featured, modern GUI) | ImageJ / µManager streaming acquisition: DE-StreamPix (realtime, continuous display and recording)

compatibility: SerialEM | Leginon | EMTools (TVIPS) | JADAS (JEOL) | others

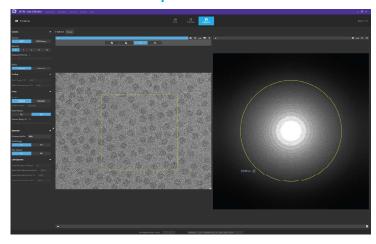
customization: software development kit (SDK) for integration with custom software

Integrating (Linear) Mode

used for all TEM applications



DE-IM Acquisition Software



DQE curves are shown for 300 kV electrons | Specifications and performance are subject to change. Example images of various camera applications were collected by researchers using one of Direct Electron's cameras (not necessarily the DE-DirectView).